DOCKET: CU-3664

## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

APPLICANT:		Kiyoshi OOI et al	)
			)
TITLE:	SE	MICONDUCTOR DEVICE SUBSTR.	ATE,
	SE	MICONDUCTOR DEVICE, AND	)
	MA	NUFACTURING METHOD	)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## **INFORMATION DISCLOSURE STATEMENT**

## Dear Sir:

The information disclosure statement submitted herewith is being filed within three months of the filing date of the application or date of entry into the national stage of an international application or before the mailing date of the first Office Action on the merits, whichever event occurs last. 37 CFR 1.97(b).

Applicants bring to the attention of the U.S. Patent Office patents, publications or other information of which the applicants are aware, which may be material to the examination of this application and in respect of which there may be a duty to disclose under 37 CFR 1.56.

The filing of this information disclosure statement shall not be construed as a representation that a search has been made (37 CFR 1.97(g)), an admission that the information cited is, or is considered to be, material to patentability or that no other material information exists.

The filing of this information disclosure statement shall not be construed as an admission against interest in any manner. Notice of January 9, 1992, 1135 O.G. 13-25, at 25.

The references submitted herein are listed on PTO-1449 form (modified) enclosed herewith. A copy of each reference listed is being furnished except any duplicate or cumulative patents or publications specified otherwise. Copies of U.S. references are not provided as a result of recent amendments to the requirements for filing Information Disclosure Statement citations.

A translation of any foreign language reference, if any, is indicated in PTO-1449 form and being submitted herein if it is readily available. Otherwise it should be construed that such translation is not readily available.

The Statement is made on the basis of the information supplied by an individual associated with the filing and prosecution of this application (37 CFR 1.56(c)).

Respectfully submitted,

March 29, 2004

Date

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Attorney for Applicant

Richard J. Streit, Reg. 25765 c/o Ladas & Parry 224 South Michigan Avenue Chicago, Illinois 60604 (312) 427-1300

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